

Material No.: 9346-05 Batch No.: 0000200571

Manufactured Date: 2018/05/08 Retest Date: 2023/05/07

Revision No: 1

Certificate of Analysis

Test	Specification	Result
Assay (HOCH2CH2OH) (by GC)	>= 99.0 %	99.9
Color (APHA)	<= 10	5
Acidity (µeq/g)	<= 0.8	0.2
Acidity (as CH ₃ COOH)(by wt)	<= 0.01 %	< 0.01
Residue after Ignition	<= 0.005 %	< 0.001
Water (H2O)(by Karl Fischer titrn)	<= 0.2 %	0.1
Chloride (Cl)	<= 1 ppm	< 1
Phosphate (PO ₄)	<= 2 ppm	< 2
Sulfate (SO ₄)	<= 2 ppm	< 2
Arsenic and Antimony (as As)	<= 0.100 ppm	< 0.100
Trace Impurities – Iron (Fe)	<= 0.2 ppm	0.1
Trace Impurities - Aluminum (Al)	<= 100.0 ppb	< 5.0
Trace Impurities - Barium (Ba)	<= 100.0 ppb	< 1.0
Trace Impurities – Boron (B)	<= 50.0 ppb	5.0
Trace Impurities - Calcium (Ca)	<= 300.0 ppb	30.0
Trace Impurities - Chromium (Cr)	<= 50.0 ppb	1.0
Trace Impurities - Copper (Cu)	<= 10.0 ppb	1.0
Trace Impurities - Gold (Au)	<= 50.0 ppb	5.0
Trace Impurities - Lead (Pb)	<= 200.0 ppb	10.0
Trace Impurities - Lithium (Li)	<= 100.0 ppb	1.0
Trace Impurities – Magnesium (Mg)	<= 100.0 ppb	1.9
Trace Impurities – Manganese (Mn)	<= 100.0 ppb	1.0
Trace Impurities - Nickel (Ni)	<= 100.0 ppb	5.0
Trace Impurities – Potassium (K)	<= 300.0 ppb	10.7

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Specification	Result
<= 300.0 ppb	13.0
<= 100.0 ppb	< 10.0
<= 100.0 ppb	< 1.0
<= 400.0 ppb	36.7
<= 200 par/ml	1
<= 10 par/ml	< 1
	<= 300.0 ppb <= 100.0 ppb <= 100.0 ppb <= 400.0 ppb <= 200 par/ml

For Microelectronic Use

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004, FSSC 22000
Paris, KY 9001:2008
Mexico City, Mexico 9001:2008
Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
Gliwice, Poland 9001:2008, 13485:2012
Selangor, Malaysia 9001:2008
Dehradun, India, 9001:2008, 14001:2004, 13485:2003
Mumbai, India, 9001:2008
Panoli, India 9001:2008

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